



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Examiner: Johnston, Phillip A.

David L. Adler, et al.

Serial No. 10/017,262

Art Unit: 2881

Filing Date: 12/14/2001

Attorney Docket No.: P960 (11.700)

Title: Photoelectron Emission Microscope for Wafer and Reticle Inspection

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Commissioner of Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

AMENDMENT AND RESPONSE TO FINAL OFFICE ACTION

Sir:

This Amendment and Response is responsive to the Office Action mailed on June 17, 2003.

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